January 2006

FDN359BN N-Channel Logic Level PowerTrench[™] MOSFET

General Description

SEMICONDUCTOR IM

This N-Channel Logic Level MOSFET is produced using Fairchild's Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance.

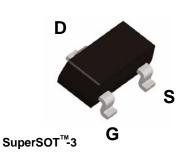
These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

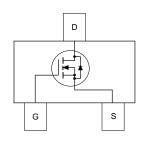
Features

• 2.7 A, 30 V. $R_{\text{DS(ON)}}$ = 0.046 Ω @ V_{GS} = 10 V

 $R_{DS(ON)}$ = 0.060 Ω @ V_{GS} = 4.5 V

- Very fast switching speed.
- Low gate charge (5nC typical)
- High performance version of industry standard SOT-23 package. Identical pin out to SOT-23 with 30% higher power handling capability.





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V _{DSS}	Drain-Source Voltage		30	V	
V _{GSS}	Gate-Source Voltage		±20	V	
I _D	Maximum Drain Current – Continuous	(Note 1a)	2.7	A	
	– Pulsed		15		
P _D	Maximum Power Dissipation	(Note 1a)	0.5	W	
		(Note 1b)	0.46		
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	250	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	75	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
359B	FDN359BN	7"	8mm	3000 units

FDN359BN

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{GS}=0~V, \qquad I_{D}=250~\mu A$	30			V
<u>ΔBVdss</u> ΔTj	Breakdown Voltage Temperature Coefficient	I_D = 250 µA,Referenced to 25°C		21		mV/°C
IDSS	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 24 \text{ V}, \qquad V_{\text{GS}} = 0 \text{ V}$			1	μA
		T _J = -55 ^C	C		10	μΑ
I _{GSS}	Gate–Body Leakage	$V_{\text{GS}} = \pm 20 \text{ V}, V_{\text{DS}} = 0 \text{ V}$			±100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{\text{DS}} = V_{\text{GS}}, \qquad I_{\text{D}} = 250 \ \mu\text{A}$	1	1.8	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 µA,Referenced to 25°C		-4		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance			0.026 0.032 0.033	0.046 0.060 0.075	Ω
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	15			Α
g fs	Forward Transconductance	$V_{DS} = 5V$, $I_{D} = 2.7 \text{ A}$		11		S
Dynamic	c Characteristics					
Ciss	Input Capacitance	$V_{DS} = 15 V$, $V_{GS} = 0 V$,		485	650	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		105	140	pF
C _{rss}	Reverse Transfer Capacitance			65	100	pF
R _G	Gate Resistance	f = 1.0 MHz		1.8		Ω
Switchin	ng Characteristics (Note 2)					
t _{d(on)}	Turn–On Delay Time	$V_{DD} = 15V, \qquad I_D = 1 A,$		7	14	ns
t _r	Turn–On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		5	10	ns
t _{d(off)}	Turn–Off Delay Time			20	35	ns
t _f	Turn–Off Fall Time			2	4	ns
Q _g	Total Gate Charge	$V_{DS} = 15 V$, $I_D = 2.7 A$,		5	7	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 V$		1.3		nC
Q _{gd}	Gate–Drain Charge			1.8		nC

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-S	ource Diode Characteristics	s and Maximum Ratings				
Is	Maximum Continuous Drain–Source Diode Forward Current				0.42	А
V_{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 V$, $I_S = 0.42 A$ (Note 2)		0.7	1.2	V
trr	Diode Reverse Recovery Time	IF = 2.7A, diF/dt = 100 A/µs		12	20	ns
Qrr	Diode Reverse Recovery Charge]		3	5	nC

otes:

 R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.

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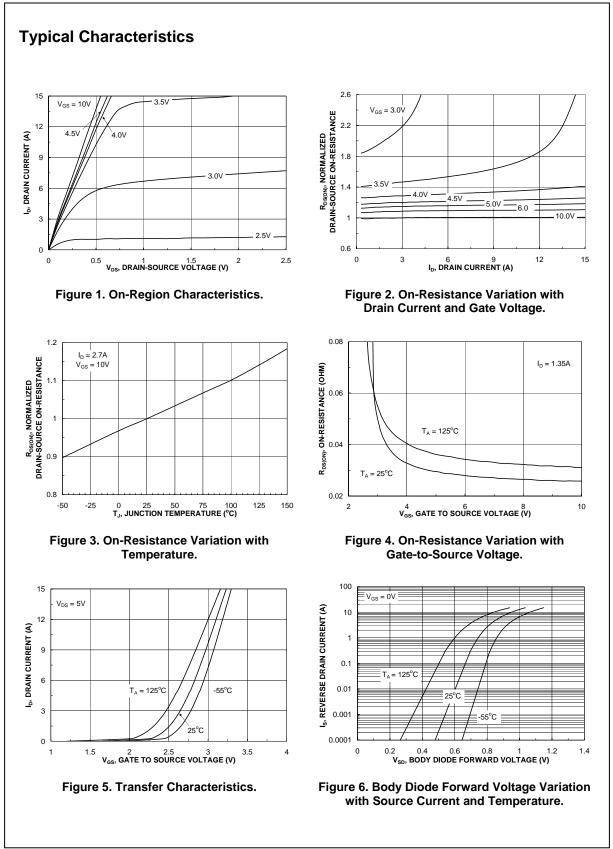


 a) 250°C/W when mounted on a 0.02 in² pad of 2 oz. copper. b) 270°C/W when mounted on a minimum pad.

Scale 1 : 1 on letter size paper

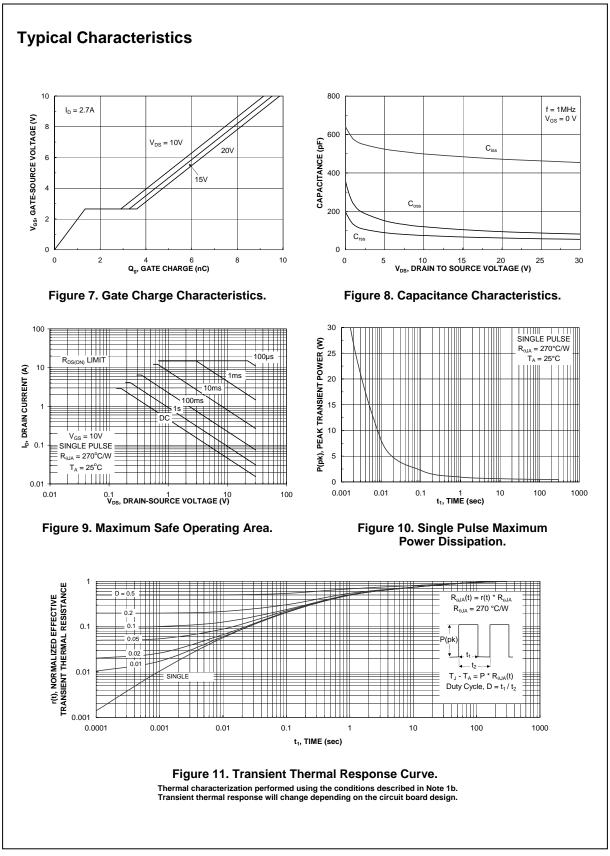
2. Pulse Test: Pulse Width $\leq 300~\mu\text{s},$ Duty Cycle $\leq 2.0\%$

FDN359BN Rev A(W)



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